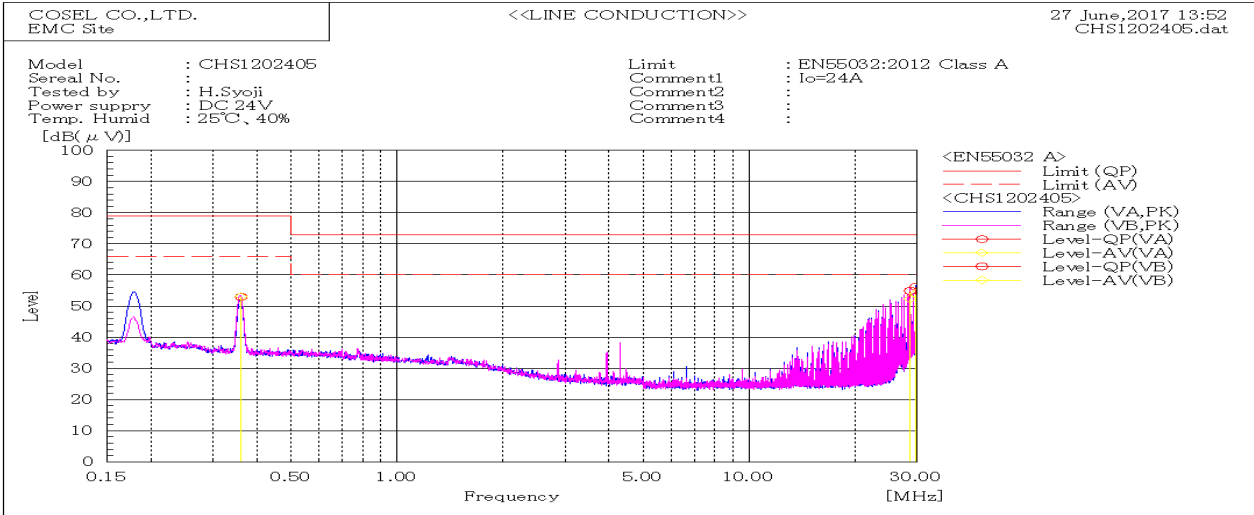
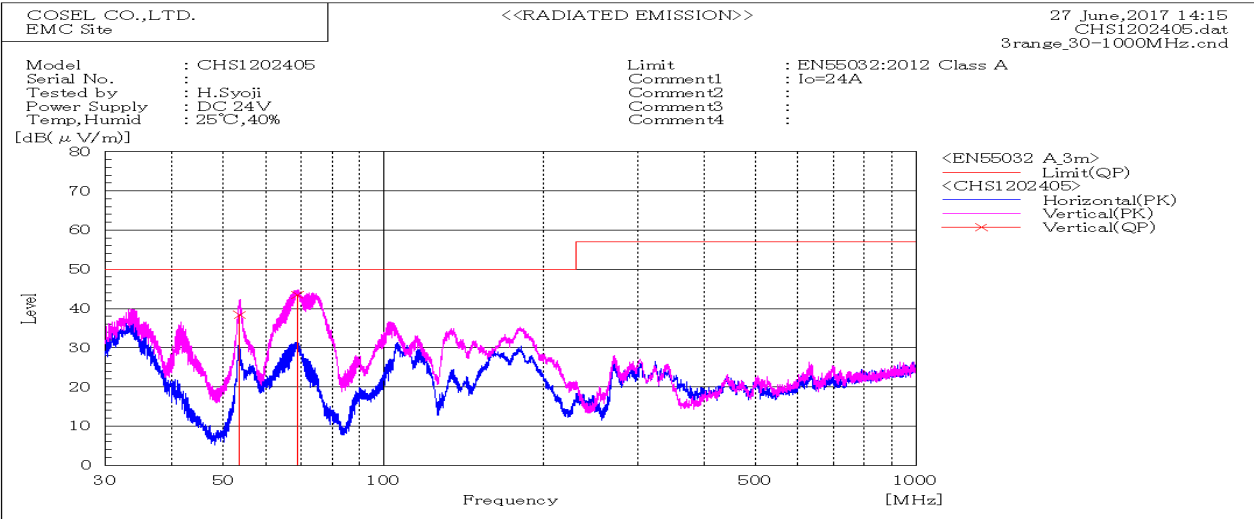


DATA SHEET		Date	27-Jun-17
Model	CHS1202405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Syoji



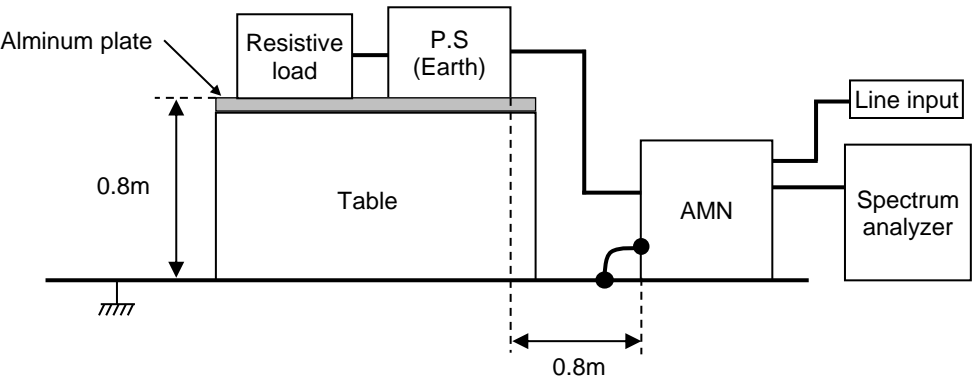
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.36051	VB	53	53.1	79	66	26	12.9	Pass	
28.7272	VA	54.9	52.3	73	60	18.1	7.7	Pass	
29.8132	VB	56.2	53.9	73	60	16.8	6.1	Pass	



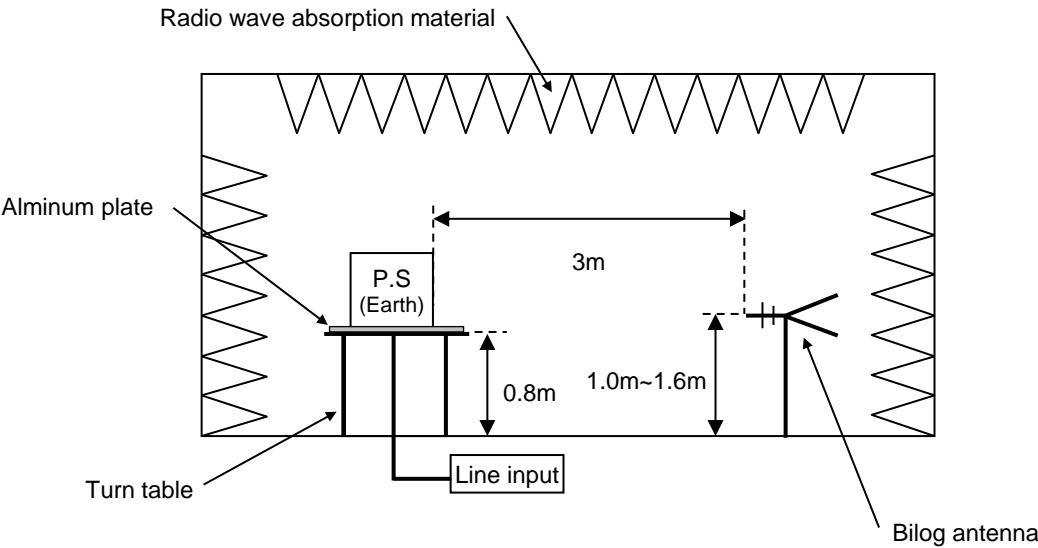
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
53.634	V	Stable	38.4	50.0	11.6	Pass	104	24	
68.881	V	Stable	43.5	50.0	6.5	Pass	124	64	

DATA SHEET		Date	27-Jun-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Syoji

1. Line conduction



2. Radiated emission

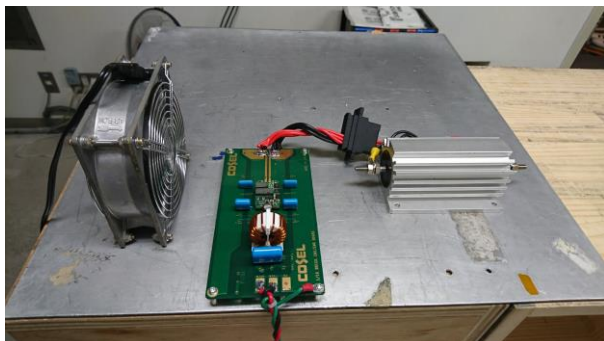


Conditions

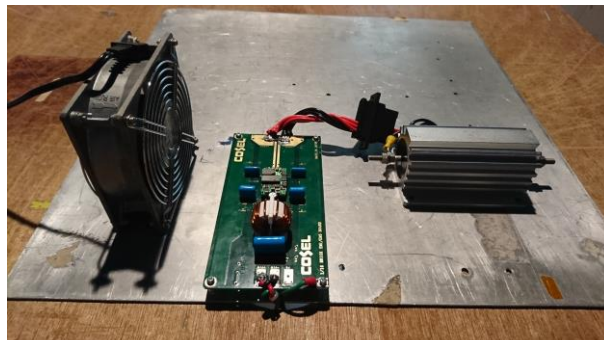
Test : EMI
Model Name : CHS12024□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

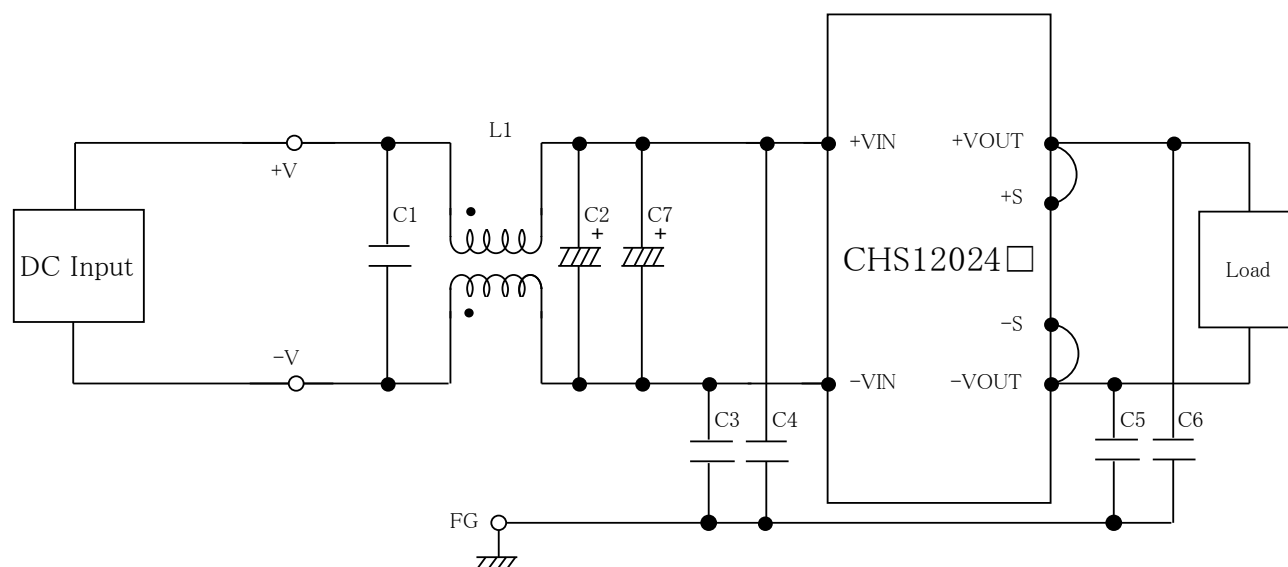


Fig.1 Testing circuitry

L1 : 0.5mH SC-15-05J (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C7 : 50V 100 μ F PWseries (nichicon)
C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)